Portable device
According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.
According to KDB447498 D01 General RF Exposure Guidance V06
The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:
[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]·[√f(GHZ)] ≤ 3.0 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- f(GHZ) is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BLE:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
BLE(1M)	2.402	-5.08	0.31	-5±1	-4	0.40	<5	0.12340	3.00	YES
	2.440	-5.15	0.31	-5±1	-4	0.40	<5	0.12437	3.00	YES
	2.480	-5.78	0.26	-5±1	-4	0.40	<5	0.12539	3.00	YES
BLE(2M)	2.402	-5.07	0.31	-5±1	-4	0.40	<5	0.12340	3.00	YES
	2.440	-5.16	0.30	-5±1	-4	0.40	<5	0.12437	3.00	YES
	2.480	-5.76	0.27	-5±1	-4	0.40	<5	0.12539	3.00	YES

SRD 2.4G

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	-1.04	0.79	-2±1	-1	0.79	<5	0.24622	3.00	YES
	2.446	-2.08	0.62	-2±1	-1	0.79	<5	0.24846	3.00	YES
	2.479	-2.6	0.55	-2±1	-1	0.79	<5	0.25013	3.00	YES

Note：This product does not support the requirements under 2.4G multiple sources.
Conclusion:
For the max result : 0.25013 ≤ 3.0 for 1g SAR, SAR is not required.

Signature: **Date:** 6/28/2024

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